

# Evolution of Heat Flow Prediction Models for FPGA Devices

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## 1 Motivation

On today's integrated circuits there is a considerable potential of generating high temperatures, due to shrinking devices and increasing frequencies. Especially FPGAs can generate local hotspots and alarmingly high temperature increases with only a rather small resource utilization [1]. For many cases the accurate temperature estimation and prediction is becoming increasingly important.

## 2 Formulation of problem

In order to predict temperatures it is mandatory to automatically determine a temperature model, as proposed in [2]. The model's parameters have to be parameterized by several measurements. Quality criteria for the obtained thermal model are predictive accuracy and the effort of model generation.

## 3 Objective target

In order to obtain an accurate thermal model, the temperature model given in [2] needs to be implemented. Its parameters will be adjusted by using combinatorial optimizing algorithms, like Simulated Annealing, evolutionary strategies and so on. The quality of the obtained temperature model will be evaluated by comparing it with the general models given in [3] and [4].

4 Time management

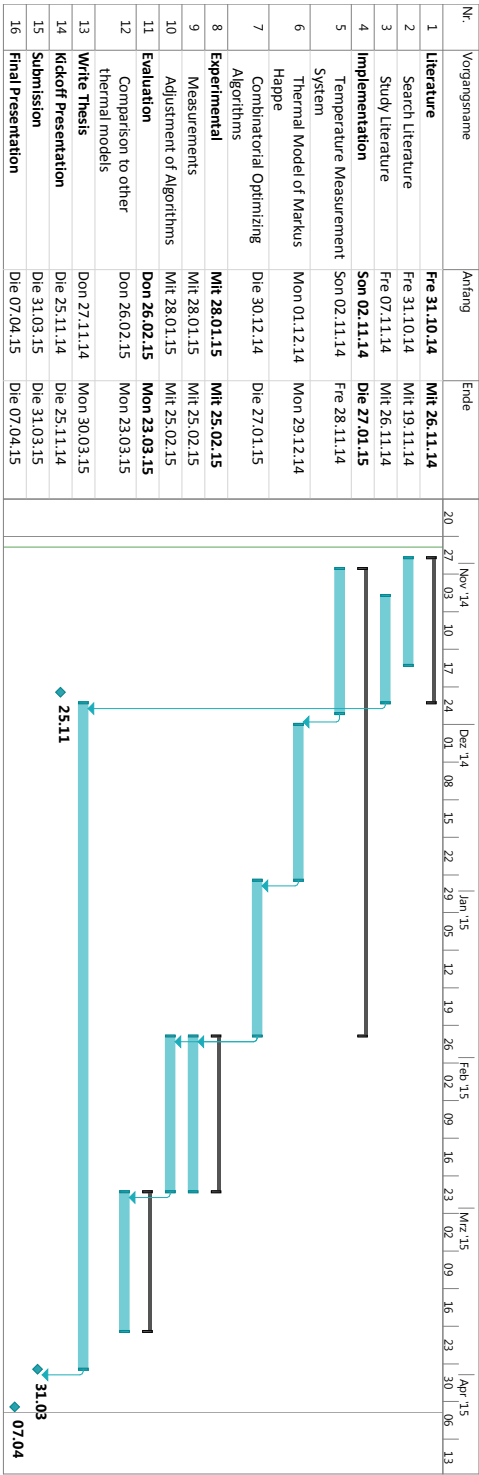


Figure 1: Time schedule

## References

- [1] Andreas Agne, Hendrik Hangmann, Markus Happe, Marco Platzner, and Christian Plessl. Seven recipes for setting your FPGA on fire A cookbook on heat generators. *Microprocessors and Microsystems*, (0):–, 2013.
- [2] Markus Happe, Andreas Agne, and Christian Plessl. Measuring and predicting temperature distributions on FPGAs at run-time. *Reconfigurable Computing and ...*, pages 55–60, 2011.
- [3] Wei Huang and Shougata Ghosh. HotSpot: A compact thermal modeling methodology for early-stage VLSI design. *Very Large Scale ...*, 14(5):501–513, 2006.
- [4] S.S. Sapatnekar and Yong Zhan. Fast Computation of the Temperature Distribution in VLSI Chips Using the Discrete Cosine Transform and Table Look-Up. *Proc. of Design Automation Conference (ASP-DAC)*, 1:87–92, 2005.